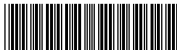


Search Notes**Application/Control No.**

10/537,174

Examiner

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**Applicant(s)/Patent under
Reexamination**

NASLUND ET AL.

Art Unit

3643

SEARCHED

Class	Subclass	Date	Examiner
54	44.1 44.3	8/11/2009	STN
	44.5 46.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search and text search, see printouts.	8/11/2009	STN